CE EMC

TEST REPORT

For

Embedded Control PC

Model: AEC-6850

Trade Name: AAEON

Issued to

AAEON Technology Inc. 5F, No. 135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R.O.C.

Issued by



Compliance Certification Services Inc. Hsintien Lab.

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TEST RESULT CERTIFICATION

Applicant: AAEON Technology Inc.

5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City,

Date of Issue: June 28, 2005

Taipei, Taiwan, R.O.C.

Manufacturer: AAEON Technology Inc.

5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City,

Taipei, Taiwan, R.O.C.

Embedded Control PC **Equipment Under Test:**

AAEON Trade Name:

AEC-6850 **Model:**

Detailed EUT Description: See Item 2 of this report

Date of Test: June 1, 2005 ~ June 20, 2005

Applicable Standard	Class/Limit/Criterion	Test Result		
EN 55022: 1998 + A1: 2000+A2: 2003	Class A	No non-compliance noted		
EN 61000-3-2: 2000	Class D	No non-compliance noted		
EN 61000-3-3: 1995 + A1: 2001	Limit	No non-compliance noted		
EN 55024:1998 + A1: 2001 + A2: 2003, includin	ng			
IEC 61000-4-2: 1995 +A1: 1998 +A2: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-3: 1995 +A1: 1998 +A2: 2000	Criterion A	No non-compliance noted		
IEC 61000-4-4: 1995 +A1: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-5: 1995 +A1: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-6: 1996 +A1: 2000	Criterion A	No non-compliance noted		
IEC 61000-4-8: 1993 +A1: 2000	Criterion A	N/A		
IEC 61000-4-11: 1994 +A1: 2000	Criterion B/C/C	No non-compliance noted		
Deviation from Applicable Standard				
None				

The above equipment was tested by Compliance Certification Services Inc. for compliance with the requirements set forth in the EMC Directive 89/336/EMC and the technical standards mentioned above. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

Approved by:

David Wang

Manager of Hsintien Laboratory

Compliance Certification Services Inc.

Reviewed by:

Vince Chiang

Assistant Manager of Hsintien Laboratory

Compliance Certification Services Inc.

2 EUT DESCRIPTION

Product	Embedded Control PC
Trade Name	AAEON
Model	AEC-6850
Housing Type	Metal case
EUT Power Rating	15VDC from AC Adaptor
AC Power During Test	230VAC / 50 Hz to AC Adaptor
AC Adaptor Manufacturer	FSP
AC Adaptor Model Number	FSP105-AGB
AC Adaptor Power Rating	I/P: 100-240VAC 50-60Hz O/P: 12VDC
AC Power Cord Type	Unshielded, 1.8m (Detachable) to AC Adaptor
DC Power Cable Type	Unshielded, 1.6m (Non-Detachable, with a core) to AC Adaptor
EUT I/O Cable Type	PS/2 one to two adaptor: Shielded, 0.15m (Detachable) S-Video: Shielded, 0.2m (Detachable)
OSC/Clock Frequency	14.31818MHz; 25MHz; 24.576MHz; 32.768kHz

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I/O PORT OF EUT

I/O PORT	ГҮРЕ	Q'TY	TESTED WITH
1). SIO Port		2	2
2). Video-out Port (VGA)		1	1
3). Video-out Port (DVI)		1	1
4). Audio out Port		1	1
5). PS/2 one to two adaptor		1/1	1/1
6). LAN Port		1	1
7). USB Port		3	3
8). S-Video in Port		1	1
	Audio in Port	1	1
9). Audio Switch out Port	Earphone Port	1	1
	Microphone Port	1	1
10). SD Slot Port		1	1
11). CF Slot Port		1	1

Note: Client consigns only one model sample (Model Number is AEC-6850) to test.

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3 TEST METHODOLOGY

3.1 EUT SYSTEM OPERATION

- 1. Windows XP boots system.
- 2. Run Emctest.exe to activate all peripherals and display "H" pattern on monitor screen.

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- 3. Run Winemc.exe and choose media player to play music.
- 4. Run Winemc.exe and choose "F:/ & G:/ & H:/" to test USB 2.0 Ports.
- 5. Run Winemc.exe and choose "C:/ & E:/ & I:/ & K:/" to test EUT.
- 6. Press the start menu, select executive and type ping 192.168.0.1 –t (EUT), ping 192.168.0.5 –t (Server Notebook).

Note: Test program is self-repeating throughout the test.

3.2 DECISION OF FINAL TEST MODE

1. The following test mode(s) were scanned during the preliminary test:

Mode:

1. NORMAL MODE

2. After the preliminary scan, the following test mode(s) was found to produce the highest emission level.

Conduction: Mode 1 **Radiation:** Mode 1

Then, the EUT configuration and cable configuration of the above highest emission mode was chosen for all final test items.

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4 SETUP OF EQUIPMENT UNDER TEST

Setup Diagram

See test photographs attached in Appendix I for the actual connections between EUT and support equipment.

Support Equipment

EUT Devices:

No	Equipment	Model #	Serial #	FCC/BSMI ID	Trade Name
1	CPU (1.3GHz)	Celeron M-1.3G, 1.356V	mFCBGA479	N/A	INTEL
2	Memory (512MB)	DDR333	N/A	N/A	DSL
3	CD ROM	SCR-242	N/A	N/A	Quanta
4	HDD	335M7616T	N/A	N/A	Toshiba
5	PCBA	GENE-8310	N/A	N/A	AAEON

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Peripherals Devices:

No	Equipment	Model	Serial No.	FCC/ BSMI ID	Trade Name	Data Cable	Power Cord
1	Player	RQ-L317	N/A	N/A	PANASONIC	Unshielded, 1.4m	N/A
2	Ear	MSB301	N/A	N/A	e-Sense	Unshielded, 2.0m	N/A
3	Ear	MSB301	N/A	N/A	e-Sense	Unshielded, 2.0m	N/A
4	PS/2 Keyboard	SK-8110	N/A	BSMI: T3A002 DoC	DELL	Shielded, 1.8m	N/A
5	PS/2 Mouse	M071KC	443029438	BSMI: R41108 DoC	DELL	Shielded, 1.8m	N/A
6	Monitor (LCD)	213T	NB21H4JX305280H	BSMI: R33475 DoC	SAMSUNG	Shielded, 1.8m with two cores	Unshielded, 1.8m
7	Monitor (LCD)	710V	GS17H9NXA05853A	BSMI: R33475 DoC	SAMSUNG	Shielded, 1.8m with two cores	Unshielded, 1.8m
8	USB 2.0 HDD	F12-UF	N/A	BSMI ID: 4912A002	TeraSyS	Shielded, 1.8m	Unshielded, 1.8m with a core
9	USB 2.0 HDD	F12-UF	N/A	BSMI ID: 4912A002	TeraSyS	Shielded, 1.8m	Unshielded, 1.8m with a core
10	USB 2.0 HDD	F12-UF	N/A	BSMI ID: 4912A002	TeraSyS	Shielded, 1.8m	Unshielded, 1.8m with a core
11	Modem	5JEG4033MKO	N/A	5RJTAI-35500-M5-E	TOP - SOLUTION	Shielded, 1.1 m	Unshielded, 1.8m
12	Modem	1414	N/A	IFAXDM1414	ACEEX	Shielded, 1.1 m	Unshielded, 1.8m
13	Monitor (TV)	KD17NS	7728	BSMI: R33475	SAMAUNG	Shielded, 1.6 m	Unshielded, 1.8m with a core
14	Server Notebook	Type 2659	N/A	BSMI: R43004	IBM	Unshielded, 20m	Unshielded, 1.8m

Note: All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test. Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

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FACILITIES AND ACCREDITATIONS

5.1 FACILITIES

All measurement facilities used to collect the measurement data are located at CCS Taiwan Hsintien Lab at No. 165, Chunghsen Road, Hsintien City, Taipei Hsien, Taiwan.

The measurement facilities are constructed in conformance with the requirements of CISPR 16-1, ANSI C63.4 and other equivalent standards.

5.2 LABORATORY ACCREDITATIONS AND LISTINGS

The test facilities used to perform Electromagnetic compatibility tests are registered or accredited by the organizations listed in the following table which includes the recognized scope specifically.

Country	Agency	Scope of Accreditation	Logo
USA	CFR 47, FCC Part 15/18 using ANSI 63.4; AS/NZS 3548; VCCI V3; CNS 13438; CNS 13439; CNS 13783; CNS 14115; CISPR 11/EN 55011; CISPR 14-1/EN 55014-1; CISPR 15/EN 55015; CISPR 22/EN 55022; EN 50081-1/EN 61000-6-3; EN 50082-1/EN 61000-6-4; IEC/EN 61000-4-2, IEC/EN 61000-4-3, IEC/EN 61000-4-4, IEC/EN 61000-4-5, IEC/EN 61000-4-6, IEC/EN 61000-4-8, IEC/EN 61000-4-11, IEC/EN 61000-3-2, IEC/EN 61000-3-3; CISPR 24/EN 55024; CISPR 14-2/EN 55014-2; EN 50081-2/EN 61000-6-1; EN 50082-2/EN 61000-6-2.		ACCREDITED 824.01
USA	FCC	3/10 meter Open Area Test Sites to perform FCC Part 15/18 measurements	F © 250366
Japan	VCCI	3/10 meter Open Area Test Sites and Line Conducted Test Room to perform conducted/radiated measurements	VCCI R-1434/1630~4 C-1511/1882
Norway	NEMKO	EN 50081-1/2, EN 50082-1/2, IEC 61000-6-1/2/3/4, EN 50091-2, EN 50130-4, EN 55011, EN 55013, EN 55014-1/2, EN 55015, EN 55022, EN 55024, EN 61000-3-2/3, EN 61326-1, IEC 61000-4-2/3/4/5/6/8/11, Cispr 16-1/2/3/4	N ELA 103
Taiwan	CNLA	47 CFR FCC Part 15 Subpart B, EN 61000-3-2, EN 61000-3-3, CNS 13439, CNS 13783-1, CNS 13438, AS/NZS 3548, VCCI, CNS 13022-1/2/3, EN 55022, EN 55013, EN 55014-1, EN 61000-4-2/3/4/5/6/8/11, ENV 50204, ENV 50141, ENV 50142	1108 ILAC MRA
Taiwan	BSMI	CNS 13438, CNS 13783-1, CNS 13439	SL2-IN-E-0005 SL2-A1-E-0005 SL2-R1-E-0005 SL2-R2-E-0005
Canada	Industry Canada	RSS212, Issue 1	Canada IC 5742

Note: No part of this report may be used to claim or imply product endorsement by CNLA, A2LA or other government agency.

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6 INSTRUMENT AND CALIBRATION

6.1 MEASURING INSTRUMENT CALIBRATION

The measuring equipment utilized to perform the tests documented in this report has been calibrated once a year or in accordance with the manufacturer's recommendations, and is traceable to recognized national standards.

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6.2 TEST AND MEASUREMENT EQUIPMENT

The following list contains measurement equipment used for testing. The equipment conforms to the requirement of CISPR 16-1, ANSI C63.2 and. other required standards.

Calibration of all test and measurement, including any accessories that may effect such calibration, is checked frequently to ensure the accuracy. Adjustments are made and correction factors are applied in accordance with the instructions contained in the respective manual.

Equipment Used for Emission Measurement

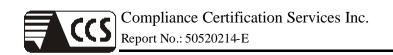
	Open Area Test Site # H							
EQUIPMENT	MFR	MODEL	SERIAL NUMBER	CAL. DUE				
SITE NSA	CCS	H Site	N/A	09/11/2005				
MEASURE RECEIVER	SCHAFFNER	SCR3501	341	09/02/2005				
SPECTRUM ANALYZER	ADVANTEST	R3132	120900002	No Calibration Required				
ANTENNA	SCHAFFNER	CBL 6112B	2801	09/24/2005				
AMPLIFIER	SCHAFFNER	CPA9231A	3613	10/08/2005				
CABLE	SUHNER	RG 214	N-TYPE#H2	12/03/2005				
THERMO- HYGRO METER	TFA	N/A	NO.1	12/22/2005				
DECOUPLING NETWORK	FCC	F-201-DCN-5-6MM	22、24	09/07/2005				

Note: The measurement uncertainty is less than +/- 3.36dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

Conducted Emission Test Site # A							
EQUIPMENT	MFR	MODEL	SERIAL NUMBER	CAL. DUE			
TEST RECEIVER	R&S	ESHS20	840455/006	02/17/2006			
LISN (EUT)	SCHWARZBECK	NSLK 8127	8127382	01/03/2006			
LISN	SOLAR	8012-50-R-24-BNC	8305114	01/03/2006			
BNC CABLE	MIYAZAKI	5D-FB	BNC A1	01/28/2006			
THERMO- HYGRO METER	ТОР	HA-202	9303-1	03/02/2006			
4-Wire ISN	R&S	ENY41	100006	07/01/2005			
2-Wire ISN	R&S	ENY22	100020	07/01/2005			

Note: The measurement uncertainty is less than +/- 2.83dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

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Power Harmonic & Voltage Fluctuation/Flicker Test Site (EN 61000-3-2&-3-3)						
Manufacturer/Type	Model No.	Serial No.	Cal. Due			
Schaffner / Signal Conditioning Unit	CCN 1000-1	72122	12/05/2005			
Schaffner / 5KVA AC Power Source	NSG 1007	55131	No Calibration Required			

Equipment Used for Immunity Measurement

ESD Test Site (EN 61000-4-2)						
Manufacturer/Type	Serial No.	Cal. Due				
Schaffner / ESD Simulator	NSG 438	129	04/20/2006			
Sato / Aneroid Barometer	7610-20	89090	09/07/2005			
TOP / Thermo-Hygro meter	HA-202	9303-1	03/02/2006			

Radiated Electromagnetic Field Immunity Test Site (EN 61000-4-3)						
Manufacturer/Type	Model No.	Serial No.	Cal. Due			
Calibration of Field	Chamber#RS	RS3H-6 / RS3V-6	07/02/2005			
Agilent / Signal Generator	E4421B	MY43350597	05/16/2006			
AR / Electric Field Probe	FP6001	305650	02/03/2006			
Boonton / RF Voltmeter	9200B	328001AE	02/23/2006			
BNC / Function Generator	625A	25451	02/17/2006			
AR / Amplifier	100W1000M1	17564	No Calibration Required			
Werlatone Inc. / Direction Coupler	C2630	4121	No Calibration Required			
Frankonia / Broadband Antenna	BTA-M	030001M	No Calibration Required			
TOP / Thermo-Hygro meter	HA-202	9303-2	03/02/2006			

Fast Transients/Burst Test Site (EN 61000-4-4)						
Manufacturer/Type	Model No.	Serial No.	Cal. Due			
Schaffner / EFT Generator	BEST EMC V2.3	200031A024SC	11/09/2005			
Schaffner / Capacitive Clamp	Clamp N/A		No Calibration Required			

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Surge Immunity Test Site (EN 61000-4-5)						
Manufacturer/Type	Model No. Serial No.		Cal. Due			
Schaffner / Surger Generator	BEST EMC V2.3	200031A024SC	11/09/2005			
Schaffner / Signal and Data Lines Coupling Network	CDN118	19328	No Calibration Required			

	CS test (EN 61000-4-6)							
Manufacturer/Type	Model No.	Serial No.	Cal. Due					
Schaffner / RF Generator	NSG 2070-1	1061	08/02/2005					
Schaffner / CDN	CDN M316	19600	08/02/2005					
Schaffner / CDN	CDN M216	19294	08/02/2005					
Schaffner / EM Clamp	KEMZ 801	19227	02/23/2006					
Schaffner / CDN	CDN A800	17885	08/02/2005					
Schaffner / CDN	CDN T002	15881	01/13/2006					
FCC / CDN	FCC-801-T8-RJ45	04025	06/24/2005					
Schaffner / Attenuator	INA2070-1	2061	No Calibration Required					
FCC / CDN	FCC-801-T4-RJ45	04031	08/19/2005					

Power Frequency Magnetic Field Immunity test (EN 61000-4-8)							
Manufacturer/Type	Model No.	Serial No.	Cal. Due				
Schaffner / Induction Coil Interface	INA 21141	6009	No Calibration Required				
Schaffner / 5KVA AC Power Source	NSG 1007	55131	No Calibration Required				
CHY/ TRMS Clamp Meter	932C	2K0900285	10/12/2005				
Sypris / Magnetic Field Meter	4080	0247	01/19/2006				

Voltage Dips/Short Intern	ruption and Voltage	Variation Immunity	test (EN 61000-4-11)	
Manufacturer/Type	Model No.	Serial No.	Cal. Due	
Schaffner / Dips/Interruption/Variations Tester	BEST EMC V2.3	200031A024SC	11/09/2005	
Protronix / Digital Power Meter	1201	201091	08/31/2005	

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7 LINE CONDUCTED & RADIATED EMISSION TEST

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7.1 LIMIT

Maximum permissible level of Line Conducted Emission

FREQUENCY	Class A	(dBuV)	Class B (dBuV)		
(MHz)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	79	66	66 - 56	56 - 46	
0.50 - 5.0	73	60	56	46	
5.0 - 30.0	73	60	60	50	

Note: The lower limit shall apply at the transition frequency.

<u>Maximum permissible level of Common Mode Conducted Emission</u> (<u>Telecommunication Ports</u>)

CLASS A

FREQUENCY	Voltage Limit (dBuV)		Current Limit (dBuA)		
(MHz)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	97 – 87	84 - 74	53 – 43	40 – 30	
0.5 - 30.0	87	74	43	30	

CLASS B

FREQUENCY	Voltage Limit (dBuV)		Current Limit (dBuA)		
(MHz)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	84 - 74	74 - 64	40 – 30	30 - 20	
0.5 - 30.0	74	64	30	20	

Note: The lower limit shall apply at the transition frequency.

Maximum permissible level of Radiated Emission measured at 10 meter

FREQUENCY	Class A (dBuV/m)	Class B (dBuV/m)		
(MHz)	Quasi-peak	Quasi-peak		
30 – 230	40	30		
230 - 1000	47	37		

Note: The lower limit shall apply at the transition frequency.

7.2 TEST PROCEDURE OF LINE CONDUCTED EMISSION

Procedure of Preliminary Test

• The EUT was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.

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- Support equipment, if needed, was placed as per EN 55022.
- All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- The test system with EUT received AC power, 230V/50Hz, through a Line Impedance Stabilization Network (LISN), which supplied power source and was grounded to the ground plane.
- All support equipment received power from a second LISN.
- The EUT test program was started. Emissions were measured on each current carrying line of the EUT using an EMI Test Receiver connected to the LISN powering the EUT.
- The Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- During the above scans, the emissions were maximized by cable manipulation.
- The test mode(s) described in Item 3.2 were scanned during the preliminary test.
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT configuration and cable configuration of the above highest emission level were recorded for reference of the final test.

Procedure of Final Test

- EUT and support equipment were set up on the test bench as per the configuration with highest emission level in the preliminary test.
- A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the Average limit in Q.P. mode, then the emission signal was re-checked using an Average detector.
- The test data of the worst-case condition(s) was recorded.

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Data Sample:

Freq. MHz	Read Level dBuV	Factor dB	Level dBuV	Limit dBuV	Over Limit dB	Reading Type (P/Q/A)	Line (L1/L2)
X.XX	42.95	0.55	43.50	73	-29.50	Q	L1

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Freq. = Emission frequency in MHz

Read Level = Uncorrected Analyzer/Receiver reading Factor = Insertion loss of LISN + Cable Loss

Level = Read Level + Factor Limit = Limit stated in standard Over Limit = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

L1 = Hot side L2 = Neutral side

Calculation Formula

Over Limit (dB) = Level (dBuV) – Limit (dBuV)

7.3 TEST PROCEDURE OF COMMON MODE CONDUCTED EMISSION FOR TELECOMMUNICATION PORT

- Selecting ISN for unscreened cable or a current probe for screened cable to take measurement.
- The port of the EUT was connected to the remote side support equipment through the ISN/Current Probe and communication in normal condition.
- Making a overall range scan by using the test receiver controlled by controller and record at least six highest emissions for showing in the test report.
- Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit.
- In case of measuring on the screened cable, the current limit shall be applied, otherwise the voltage limit should be applied.
- The following test mode(s) were scanned during the preliminary test:

Mode:

1 100 Mbps

• After the preliminary scan, we found the following test mode(s) producing the highest emission level and test data of the worst case was recorded.

Mode: 1

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Data Sample:

Freq. MHz	Read Level dBuV	Factor dB	Level dBuV	Limit dBuV	Over Limit dB	Reading Type (P/Q/A)
x.xx	62.95	0.55	63.50	87	-23.50	Q

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Freq. = Emission frequency in MHz

Read Level = Uncorrected Analyzer/Receiver reading Factor = Insertion loss of ISN + Cable Loss

Level = Read Level + Factor
Limit = Limit stated in standard
Over Limit = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

Calculation Formula

Over Limit (dB) = Level (dBuV) – Limit (dBuV)

7.4 TEST PROCEDURE OF RADIATED EMISSION

Procedure of Preliminary Test

- The equipment was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane. When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
 - Support equipment, if needed, was placed as per EN 55022.
 - All I/O cables were positioned to simulate typical usage as per EN 55022.
 - The EUT received AC power source, 230V/50Hz, from the outlet socket under the turntable. All support equipment received power from another socket under the turntable.
 - Mains cables, telephone lines or other connections to auxiliary equipment located outside the test are shall drape to the floor, be fitted with ferrite clamps or ferrite tubes placed on the floor at the point where the cable reaches the floor and then routed to the place where they leave the turntable. No. extension cords shall be used to mains receptacle.
 - The antenna was placed at 10 meter away from the EUT as stated in EN 55022. The antenna connected to the Spectrum Analyzer via a cable and at times a pre-amplifier would be used.
 - The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.

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- The test mode(s) described in Item 3.2 were scanned during the preliminary test:
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for the final test.

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Procedure of Final Test

- EUT and support equipment were set up on the turntable as per the configuration with highest emission level in the preliminary test.
- The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Q.P. reading is presented.

Data Sample:

Freq. MHz	Amptd dBuV/m	Margin dB	Limit dBuV/m	Reading dBuV	Factor dB/m	Reading Type (P/Q/A)	Pol. (H/V)
x.xx	26.2	-13.8	40	14	12.2	Q	Н

Freq. = Emission frequency in MHz

Reading = Uncorrected Analyzer/Receiver reading

Factor = Antenna Factor + Cable Loss + Attenuator (3/6/10dB) – Amplifier Gain

Amptd = Uncorrected Analyzer/Receiver reading + Factor

Limit = Limit stated in standard

Margin = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

H = Antenna Polarization: Horizontal V = Antenna Polarization: Vertical

Calculation Formula

Margin (dB) = Amptd (dBuV/m) – Limit (dBuV/m)

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7.5 TEST RESULTS

Line Conducted Emission

Model: AEC-6850 **Test Mode:** Mode 1

Temperature: 24 °C **Humidity:** 65% RH

Test Results: Passed **Tested by:** MATT HSU

(The chart below shows the highest readings taken from the final data, see **Appendix III** for details.)

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Test Mode: Mode 1

	Six Highest Conducted Emission Readings						
Fre	quency Ran	ge Investiga	ated	150 kHz to 30 MHz			
Freq (MHz)	Read Level (dBuV)	Factor (dB)	Level (dBuV)	Limit Line (dBuV)	Over Limit (dB)	Reading Type (P/Q/A)	Line (L1/L2)
0.307	54.30	0.19	54.49	79.00	-24.51	P	L1
0.363	54.59	0.20	54.79	79.00	-24.21	P	L1
0.461	55.30	0.20	55.50	79.00	-23.50	P	L1
0.595	54.94	0.21	55.15	73.00	-17.85	P	L1
0.358	52.75	0.17	52.92	79.00	-26.08	P	L2
0.535	52.02	0.21	52.24	73.00	-20.76	P	L2

NOTE: The emission level was or more than 2dB below the Average limit, so no re-check anymore.

Common Mode Conducted Emission

Six Highest Conducted Emission Readings						
Frequency F	Range Investi	gated		150 kHz to 30 MHz		
Freq (MHz)	Read Level (dBuV)	Factor (dB)	Level (dBuV)	Limit Line (dBuV)	Over Limit (dB)	Reading Type (P/Q/A)
0.302	42.23	10.47	52.70	91.19	-38.49	P
5.898	48.71	10.30	59.01	87.00	-27.99	P
9.451	49.27	10.27	59.54	87.00	-27.46	P
12.188	51.54	10.29	61.83	87.00	-25.17	P
13.408	51.44	10.31	61.75	87.00	-25.25	P
15.552	50.37	10.32	60.69	87.00	-26.31	P
26.001	48.56	10.36	58.92	87.00	-28.08	P

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Radiated Emission

Model: AEC-6850 Test Mode: Mode 1

Temperature: 28°C **Humidity:** 70 % RH

Test Results: Passed Tested by: ALEX PAN

(The chart below shows the highest readings taken from the final data, see **Appendix III** for details.)

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Six Highest Radiated Emission Readings							
Frequency	Range Inve	estigated		30 MHz to 1000 MHz at 10m			
Freq (MHz)	Amptd (dBuV/m)	Margin (dB)	Limit (dBuV/m)	Reading (dBuV)	Factor (dB/m)	Reading Type (P/Q/A)	Pol. (H/V)
119.3000	27.16	-12.84	40.00	41.87	-14.71	P	${f V}$
217.2400	28.86	-11.14	40.00	43.78	-14.92	P	V
232.8900	34.39	-12.61	47.00	47.96	-13.57	P	\mathbf{V}
405.8700	34.42	-12.58	47.00	41.04	-6.62	P	V
133.5200	27.25	-12.75	40.00	42.39	-15.14	P	H
406.1900	34.52	-12.48	47.00	41.13	-6.61	P	H

NOTE: None.

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8 POWER HARMONICS TEST

Port : AC Power Port

Basic Standard : EN 61000-3-2 (2000)

Limits : \square CLASS A; \overline{V} CLASS D

Teste d by : ELVIS ZENG

Temperature : 19°C **Humidity** : 59%

Limit:

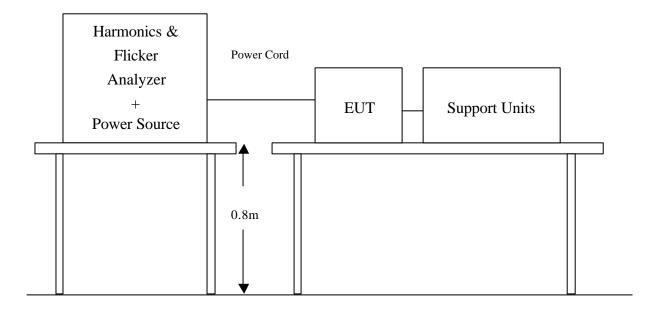
Limits for Class A equipment			
Harmonics	Max. permissible		
Order	harmonics current		
n	A		
Od	d harmonics		
3	2.30		
5	1.14		
7	0.77		
9	0.40		
11	0.33		
13	0.21		
15<=n<=39	0.15x15/n		
Eve	en harmonics		
2	1.08		
4	0.43		
6	0.30		
8<=n<=40	0.23x8/n		

	Limits for Class D equip	oment
Harmonics Order n	Max. permissible harmonics current per watt mA/W	Max. permissible harmonics current
	Odd Harmonics only	7
3	3.4	2.30
5	1.9	1.14
7	1.0	0.77
9	0.5	0.40
11	0.35	0.33
13	0.30	0.21
15<=n<=39	3.85/n	0.15x15/n

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Block Diagram of Test Setup:



Test Procedure:

- a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.
- b. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the time necessary for the EUT to be exercised.

Test Result:

	FAIL
Note: No function degraded during the tests.	

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9 POWER VOLTAGE FLUCTUATION / FLICKER TEST

Port : AC Power Port

Basic Standard : EN 61000-3-3 (1995 + A1: 2001)

Limits : § of EN 61000-3-3

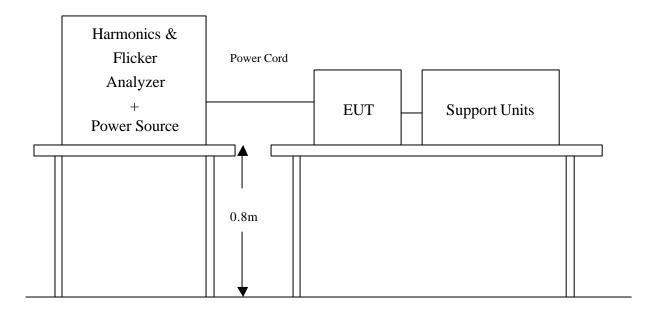
Tested by : ELVIS ZENG

Temperature : 19°C **Humidity** : 59%

Limit:

TEST ITEM	LIMIT	REMARK
P_{st}	1.0	P_{st} means short-term flicker indicator.
P _{lt}	0.65	P _{lt} means long-term flicker indicator.
T _{dt} (ms)	500	T_{dt} means maximum time that dt exceeds 3.3 %.
d _{max} (%)	4%	d _{max} means maximum relative voltage change.
dc (%)	3.3%	dc means relative steady-state voltage change

Block Diagram of Test Setup:



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Test Procedure:

- The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the most unfavorable sequence of voltage changes under normal operating conditions.
- During the flick measurement, the measure time shall include that part of whole operation cycle in which the EUT produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

Test Result: (See Appendix II for details)

TEST PARAMETER	MEASUREMENT VALUE	LIMIT	RESULT
P _{st}	0.128	1.0	Pass
P_{lt}	0.056	0.65	Pass
T _{dt} (ms)	-0.19	500	Pass
d _{max} (%)	0.14	4%	Pass
dc (%)	0	3.3%	Pass

Note: None.

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10 ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port : Enclosure

Basic Standard: IEC/EN 61000-4-2

Test Level : $\pm 8 \text{ kV (Air Discharge)}$

±4 kV (Contact Discharge) ±4 kV (Indirect Discharge)

Performance Criterion: B (Standard Required)

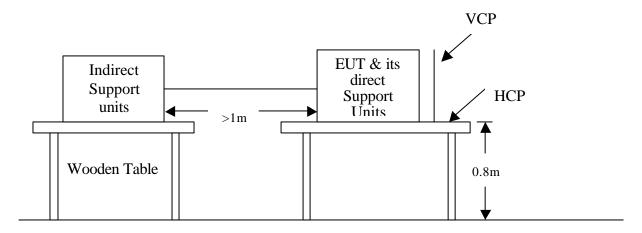
Tested by : ELVIS ZENG

Temperature : 19°C **Humidity** : 59%

Pressure : 1005mbar

Block Diagram of Test Setup:

(The 470 k ohm resistors are installed per standard requirement.)



Ground Reference Plane

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Test Procedure:

- 1. The EUT was located 0.1 m minimum from all sides of the HCP.
- 2. The indirect support units were located 1 m minimum away from the EUT, but direct support unit was/were located at same location as EUT on the HCP and keep at a distance of 10 cm with EUT.

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- 3. As per the requirement of EN 55024; applying direct contact discharge at the sides other than front of EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.
- 4. Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.
- 5. The application of ESD to the contact of open connectors is not required.
- 6. The EUT direct connection units also need to be applied ESD at the port of EUT cable connected.
- 7. Putting a mark on EUT to show tested points. The following test condition was followed during the tests.

Note: As per IEC/EN 61000-4-2, two 470k bleed resistors cable is connected between the EUT and HCP during the test applicable for power ungrounded or battery operating unit only.

The electrostatic discharges were applied as follows:

Amount of discharge	Voltage	Coupling	Result (Pass/Fail)
Mini 10 /Point	$\pm 8 \text{ kV}$	Air Discharge	No Discharge point
Mini 25 /Point	± 4 kV	Contact Discharge	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge HCP (Front)	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Right)	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Left)	Pass
Mini 25 /Point	$\pm 4 \text{ kV}$	Indirect Discharge VCP (Back)	Pass

^{**}For the tested points to EUT, please refer to attached page.
(Blue arrow mark for contact discharge and red arrow mark for air discharge)

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Performance & Result:

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.				
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.				
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.				
Oł	Observation: No function degraded during the tests.					

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The Tested Points of EUT

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Photo 3 of 5



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11 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port : Enclosure

Basic Standard: IEC/EN 61000-4-3

Requirements : 3 V/m / with 80% AM. 1kHz Modulation.

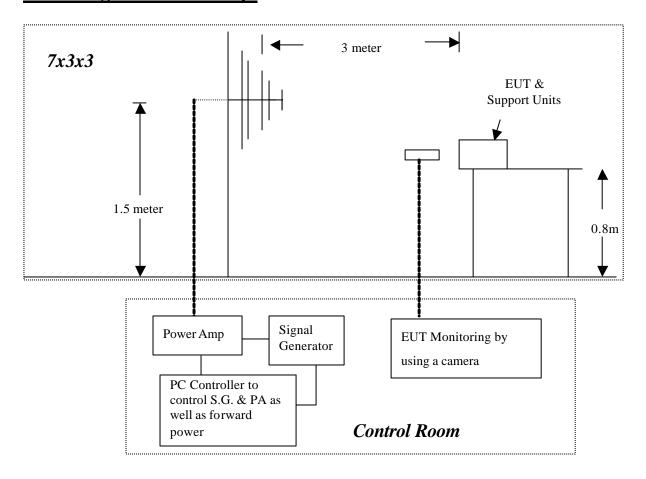
Performance Criterion: A (Standard Required)

Tested by : ELVIS ZENG

Temperature : 19°C **Humidity** : 59%

Pressure: 1005mbar

Block Diagram of Test Setup:



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Test Procedure:

1. The EUT and support units were located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity.

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- 2. Adjusting the cables to be exposed to the electromagnetic filed as possible.
- 3. Performing a Radiated Emission Scan in range of 80 to 1000 MHz prior to do RS test and records the more higher emission frequencies for the reference of RS test, due to antenna effectiveness.
- 4. Adjusting the monitoring camera to monitor the "H" message as clear as possible.
- 5. Setting the testing parameters of RS test software per IEC 61000-4-3.
- 6. Referring to the tested data of step 3 to performing the RS test from 80 to 1000 MHz.
- 7. Recording the test result in following table.
- 8. Changing the EUT to the other side and repeat step 3 to 6, until 4 sides of EUT were verified.

IEC 61000-4-3 Final test conditions:

Test level : 3V/m

Steps : 1 % of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)
80-1000	3V/m	Yes	Н	Front	Pass
80-1000	3V/m	Yes	V	Front	Pass
80-1000	3V/m	Yes	Н	Right	Pass
80-1000	3V/m	Yes	V	Right	Pass
80-1000	3V/m	Yes	Н	Back	Pass
80-1000	3V/m	Yes	V	Back	Pass
80-1000	3V/m	Yes	Н	Left	Pass
80-1000	3V/m	Yes	V	Left	Pass

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Performance & Result:

\boxtimes	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.			
	Criterion B:	3: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.			
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.			
Ol	Observation: No function degraded during the tests.				

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12 FAST TRANSIENTS/BURST IMMUNITY TEST

Port : AC Power Port and RJ45 Port

Basic Standard: IEC/EN 61000-4-4

Requirements : $\pm 1 \text{ kV for AC Power Port}$

 \pm 0.5kV for RJ45 Port

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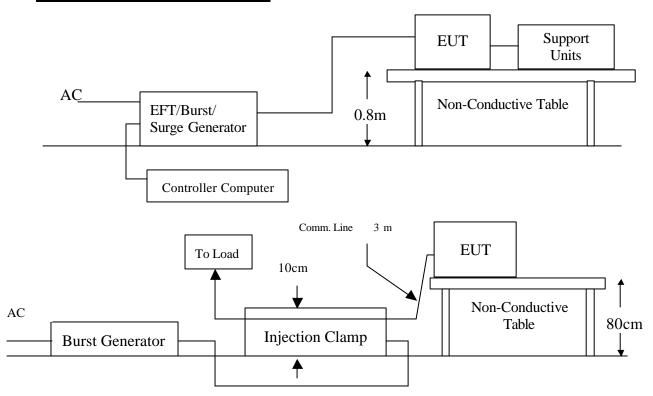
Performance Criteria: B (Standard Required)

Teste d by : MATT HSU

Temperature : 19°C **Humidity** : 59%

Pressure : 1005mbar

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground reference plane.
- 2. A 1.0 meter long power cord was attached to EUT during the test.
- 3. The length of communication cable between communication port and clamp was keeping within 1 meter.
- 4. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 5. Recorded the test result as shown in following table.

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Test conditions:

Impulse Frequency: 5kHz
Tr/Th: 5/50ns
Burst Duration: 15ms
Burst Period: 300ms

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L	± 1	Direct	Pass
N	± 1	Direct	Pass
PE	± 1	Direct	Pass
L+N	± 1	Direct	Pass
L + PE	± 1	Direct	Pass
N + PE	± 1	Direct	Pass
L + N + PE	± 1	Direct	Pass
RJ45	±0.5	Clamp	Pass

Performance & Result:

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.	
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
Oł	Observation: No function degraded during the tests.		

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13 SURGE IMMUNITY TEST

Port : AC Power Port

Basic Standard: IEC/EN 61000-4-5

Requirements : $\pm 1 \text{ kV}$ (Line to Line) for AC Power Port

± 2 kV (Line to Ground) for AC Power Port

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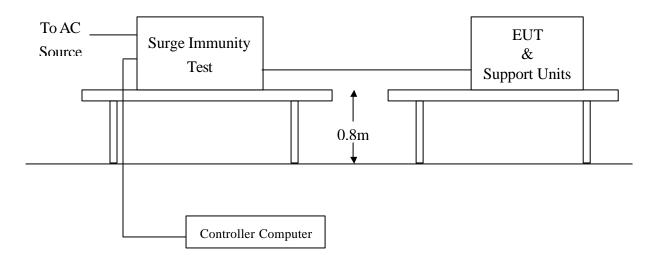
Performance Criteria: B (Standard Required)

Teste d by : ELVIS ZENG

Temperature : 19°C **Humidity** : 59%

Pressure: 1005mbar

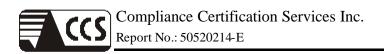
Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground floor.
- 2. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 3. Recorded the test result as shown in following table.

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Test conditions:

Voltage Waveform : 1.2/50 us Current Waveform : 8/20 us

Polarity : Positive/Negative Phase angle : 0°, 90°, 270°

Number of Test : 5

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Result (Pass/Fail)
L1-L2	1	Positive	Capacitive	Pass
L1-PE	2	Positive	Capacitive	Pass
L2-PE	2	Positive	Capacitive	Pass
L1-L2	1	Negative	Capacitive	Pass
L1-PE	2	Negative	Capacitive	Pass
L2-PE	2	Negative	Capacitive	Pass

Performance & Result:

Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
	Where normal functioning of LAN can't be achieved because of the impact of JT, no test be required.

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14 CONDUCTED DISTRBANCE/INDUCED RADIO-FREQUENCY FIELD IMMUNITY TEST

Port : AC Power Port and RJ45 Port

Basic Standard : IEC/EN 61000-4-6

Requirements : 3 V, with 80% AM. 1kHz Modulation.

Injection Method : CDN-M3 for AC Power Port

CDN-T4 for RJ45 Port

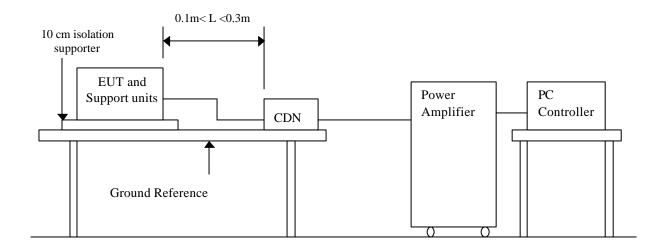
Performance Criterion: A (Standard Required)

Tested by : ELVIS ZENG

: 19°C **Temperature** Humidity : 59%

Pressure : 1005mbar

Block Diagram of Test Setup:



Test Procedure:

- The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- 2. Set the testing parameters of CS test software as per IEC/EN 61000-4-6.
- 3. Recorded the test result in following table.

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Test conditions:

Frequency Range : 0.15MHz-80MHz
Frequency Step : 1% of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	3V	Yes	Pass

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Performance & Result:

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.	
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
Ol	Observation: No function degraded during the tests.		

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15 POWER FREQUENCY MAGNETIC FIELD IMMUNITY **TEST**

Port : Enclosure

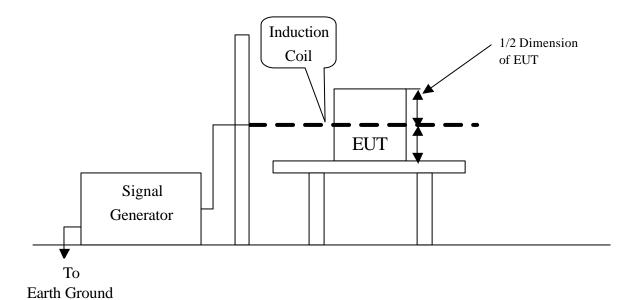
Basic Standard : IEC/EN 61000-4-8

Requirements : 1 A/m

Performance Criterion: A (Standard Required)

Tested by : N/A **Temperature** : N/A Humidity : N/A **Pressure** : N/A

Block Diagram of Test Setup:



Test Procedure:

- The EUT and support units were located on Ground Reference Plane with the interposition of a 0.1 m thickness insulation support.
- Put the induction coil on horizontal direction. (X direction)
- 3. Recorded the test result as shown in following table.
- 4. Rotated the induction coil by 90° (Y direction) then repeat step 3.
- Rotated the induction coil by 90° (Z direction) then repeat step 3.

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Test conditions:

Field Strength: 1A/m Power Freq.: 50Hz Orientation: X, Y, Z

Orientation	Field	Result (Pass/Fail)	Remark

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Performance &	& Result:
Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
	☐ PASS ☐ FAIL
Observation:	The EUT is not containing any component that is susceptible to a 50 Hz or 60 Hz magnetic field. Therefore, this requirement is not applicable to the EUT.

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16 VOLTAGE DIPS / SHORT INTERRUPTIONS

Port : AC Power Port

Basic Standard: IEC/EN 61000-4-11

Requirement: PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

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Test Interval : Min. 10 sec.
Tested by : ELVIS ZENG

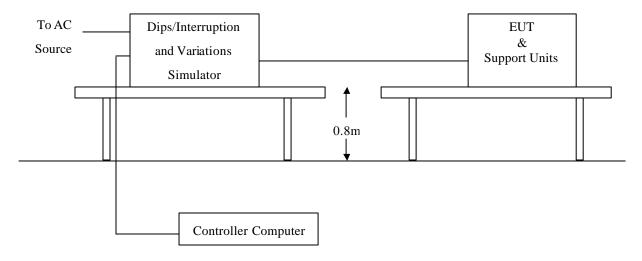
Temperature : 19°C **Humidity** : 59%

Pressure : 1005mbar

Voltage	Test Level % U _T	Reduction (%)	Duration (periods)	Performance Criterion
Dips	<5	>95	0.5	В
	70	30	25	С

Voltage Interruptions	Test Level % U _T	Reduction (%)	Duration (periods)	Performance Criterion
Interruptions	<5	>95	250	С

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located on a wooden table, 0.8 m away from ground floor.
- 2. Set the parameter of tests and then Performed the test software of test simulator.
- 3. Changed Condition to occur at 0 degree crossover point of the voltage waveform.
- 4. Recorded the test result in test record form.

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Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10 sec. minimum (Between each test event)

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Voltage Dips:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Meet Performance Criterion
0	100	0.5	Normal	A
70	30	25	Normal	A

Voltage Interruptions:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Meet Performance Criterion
0	100	250	EUT shut down, but EUT can be auto recovered after it restart.	С

Note: "Normal" means no any functions degrade during and after the test.

Performance & Result:

Criterion A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.

Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

Criterion C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

	☐ FAIL
Observation: No function degraded during	g the tests.

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APPENDIX I - PHOTOGRAPHS OF TEST SETUP

LINE CONDUCTED EMISSION TEST (EN 55022)





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COMMON MODE CONDUCTED EMISSION TEST





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RADIATED EMISSION TEST





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POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST





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ELECTROSTATIC DISCHARGE TEST



RADIATED ELECTROMAGNETIC FIELD TEST



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FAST TRANSIENTS/BURST TEST



(IEC 61000-4-4 FOR I/O)



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SURGE IMMUNITY TEST



CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST



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(IEC 61000-4-6 FOR I/O)



VOLTAGE DIPS / INTERRUPTION TEST

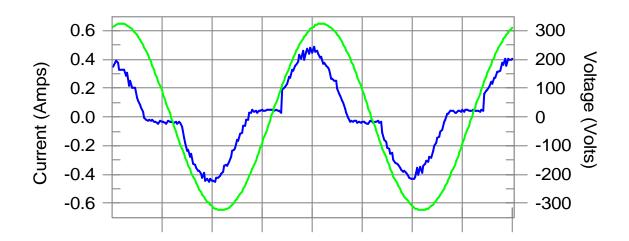


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APPENDIX II – TEST RESULT OF EN 61000-3/2-3

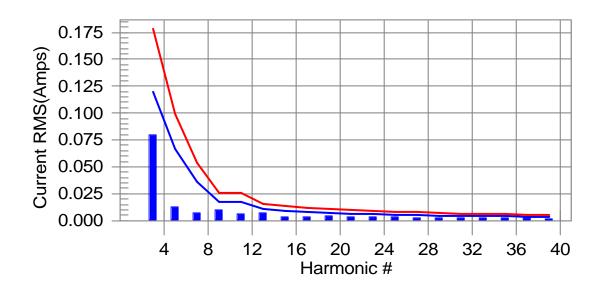
Test Result: Pass Source qualification: Normal

Current & voltage waveforms



Harmonics and Class D limit line

European Limits



Test result: Pass Worst harmonic was #25 with 45.56 % of the limit.

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Test Result: Pass Source qualification: Normal

THC(A): 0.082 I-THD(pk%): 51.783 POHC(A): N/A POHC Limit(A): N/A

Highest parameter values during test:

V_RMS (Volts): 230.10

 I_Peak (Amps):
 0.486
 I_RMS (Amps):
 0.249

 I_Fund (Amps):
 0.247
 Crest Factor:
 2.421

 Power (Watts):
 51
 Power Factor:
 0.895

Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2	0.000						
3	0.078	0.120	65.6	0.079	0.178	44.55	Pass
4	0.000						
5	0.012	0.066	17.4	0.013	0.099	12.60	Pass
6	0.000						_
7	0.006	0.036	15.9	0.007	0.054	13.49	Pass
8	0.000						_
9	0.009	0.017	53.3	0.010	0.026	38.91	Pass
10	0.000						_
11	0.002	0.017	15.5	0.006	0.026	23.13	Pass
12	0.000	0.044	50.0	0.007	0.046	40.40	D
13	0.006	0.011	53.3	0.007	0.016	42.18	Pass
14 15	0.000 0.003	0.009	31.3	0.004	0.014	26.72	Pass
16	0.003	0.009	31.3	0.004	0.014	20.72	Pass
17	0.002	0.008	27.3	0.003	0.012	26.29	Pass
18	0.002	0.006	21.3	0.003	0.012	20.29	Fa55
19	0.003	0.007	46.4	0.004	0.011	38.06	Pass
20	0.000	0.001	-101-1	0.004	0.011	00.00	1 400
21	0.002	0.006	37.1	0.003	0.010	30.67	Pass
22	0.000	0.000	• • • • • • • • • • • • • • • • • • • •	0.000	0.0.0	00.0.	. 455
23	0.002	0.006	39.7	0.003	0.009	36.61	Pass
24	0.000						
25	0.003	0.006	51.2	0.004	0.008	45.56	Pass
26	0.000						
27	0.002	0.005	42.6	0.003	800.0	35.57	Pass
28	0.000						
29	0.002	0.005	42.9	0.003	0.007	36.70	Pass
30	0.000						
31	0.002	0.004	39.4	0.002	0.006	35.47	Pass
32	0.000						_
33	0.001	0.004	36.6	0.002	0.006	33.11	Pass
34	0.000	0.001	20.2	0.000	0.000	05 -0	
35	0.002	0.004	39.6	0.002	0.006	35.79	Pass
36	0.000	0.004	40.7	0.000	0.005	40.65	D
37	0.002	0.004	48.7	0.002	0.005	42.25	Pass
38	0.000	0.004	40.0	0.000	0.005	20 50	Dana
39 40	0.001	0.004	40.8	0.002	0.005	36.58	Pass
40	0.000						

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Test Result: Pass Source qualification: Normal

Highest parameter values during test:

Voltage (Vrms): 230.10

 I_Peak (Amps):
 0.486
 I_RMS (Amps):
 0.249

 I_Fund (Amps):
 0.247
 Crest Factor:
 2.421

 Power (Watts):
 51
 Power Factor:
 0.895

Harm#	Harmonics V-rms	Limit V-rms	% of Limit	Status
2	0.127	0.460	27.56	ок
3	0.381	2.068	18.45	OK
4	0.047	0.460	10.16	OK
5	0.034	0.919	3.66	OK
6	0.065	0.460	14.19	OK
7	0.034	0.690	4.87	OK
8	0.037	0.460	8.14	OK
9	0.050	0.460	10.96	OK
10	0.020	0.460	4.33	OK
11	0.045	0.230	19.68	OK
12	0.024	0.230	10.30	OK
13	0.046	0.230	19.91	OK
14	0.020	0.230	8.60	OK
15	0.024	0.230	10.52	OK
16	0.016	0.230	7.07	OK
17	0.020	0.230	8.59	OK
18	0.035	0.230	15.35	OK
19	0.017	0.230	7.36	OK
20	0.018	0.230	8.04	OK
21	0.023	0.230	10.22	OK
22	0.024	0.230	10.40	OK
23	0.075	0.230	32.78	OK
24	0.025	0.230	10.76	OK
25	0.067	0.230	29.31	OK
26	0.036	0.230	15.57	OK
27	0.028	0.230	12.04	OK
28	0.036	0.230	15.74	OK
29	0.025	0.230	11.06	OK
30	0.065	0.230	28.45	OK
31	0.015	0.230	6.69	OK
32	0.025	0.230	10.85	OK
33	0.018	0.230	7.62	OK
34	0.010	0.230	4.48	OK
35	0.024	0.230	10.51	OK
36	0.010	0.230	4.27	OK
37	0.016	0.230	7.12	OK
38	0.008	0.230	3.40	OK
39	0.009	0.230	3.75	OK
40	0.010	0.230	4.42	OK

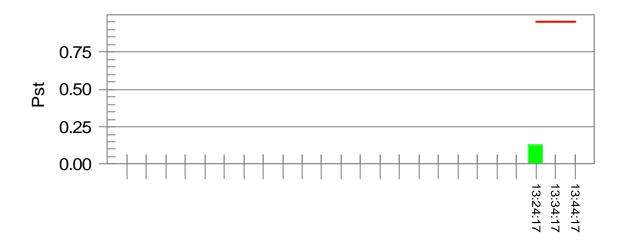
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Test Result: Pass Status: Test Completed

Pst_i and limit line

European Limits



Time is too short for Plt plot

Parameter values recorded during the test:

Vrms at the end of test (Volt):	229.78			
Highest dt (%):	-0.19	Test limit (%):	3.14	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.00	Test limit (%):	3.14	Pass
Highest dmax (%):	0.14	Test limit (%):	3.80	Pass
Highest Pst (10 min. period):	0.128	Test limit:	0.950	Pass
Highest Plt (2 hr. period):	0.056	Test limit:	0.617	Pass

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APPENDIX III - TEST RESULT OF FINAL DATAS

Conducted Emission Plot

Radiated Emission Data

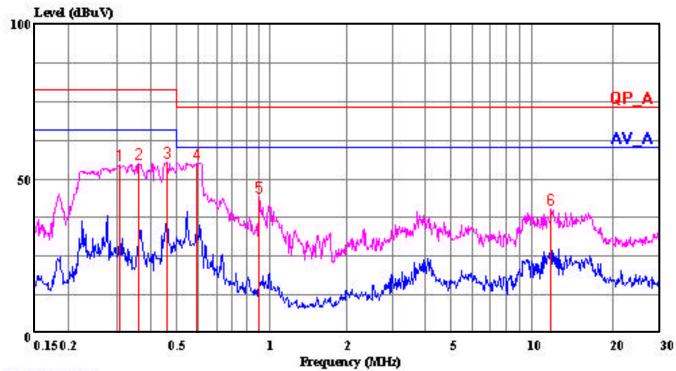
Page 53 Rev. 00



No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C.

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 24 File#: 50520214CA.EMI Date: 2005-06-01 Time: 15:01:30



(Conduction A)

Trace: 23 22 Ref Trace:

Condition: LINE

Report No. : 50520214 Test Engr. : MATT HSU

Company : AAEON Technology Inc.

EUT : AEC-6850

Test Config : EUT / ALL PERIPHERALS Type of Test: EN 55022 CLASS A Mode of Op. : NORMAL MODE

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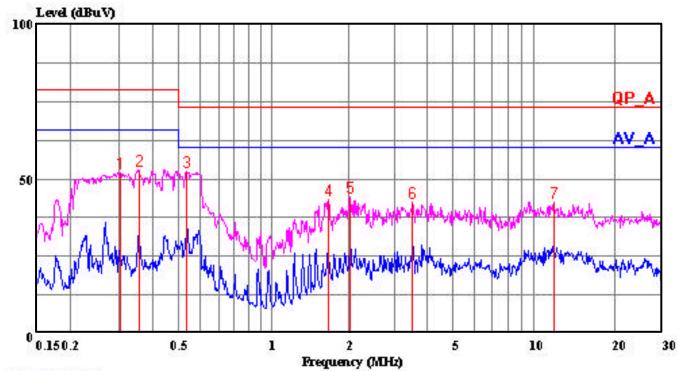
		Read			Limit	Over	
	Freq	Level	Factor	Level	Line	Limit	Remark
	MHz	dBuV	dВ	dBuV	dBuV	dВ	
1	0.307	54.30	0.19	54.49	79.00	-24.51	Peak
2	0.363	54.59	0.20	54.79	79.00	-24.21	Peak
3	0.461	55.30	0.20	55.50	79.00	-23.50	Peak
4	0.595	54.94	0.21	55.15	73.00	-17.85	Peak
5	1.005	43.72	0.22	43.94	73.00	-29.06	Peak
6	11.870	39.31	0.94	40.25	73.00	-32.75	Peak



No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C.

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 19 File#: 50520214CA.EMI Date: 2005-06-01 Time: 14:23:46



(Conduction A)

Trace: 18 17 Ref Trace:

Condition: NEUTRAL
Report No. : 50520214
Test Engr. : MATT HSU

Company : AAEON Technology Inc.

EUT : AEC-6850

Test Config : EUT / ALL PERIPHERALS Type of Test: EN 55022 CLASS A Mode of Op. : NORMAL MODE

Page:	1	
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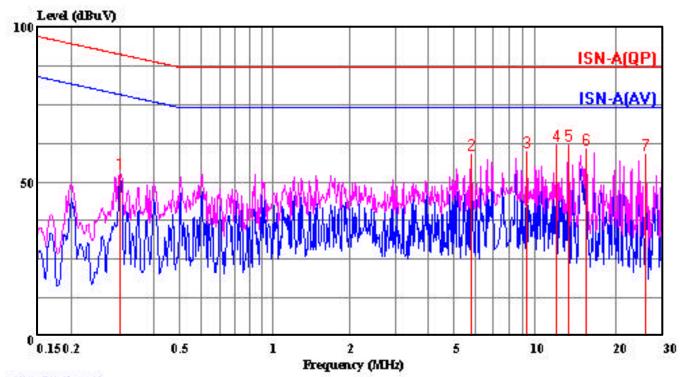
		Read			Limit	Over	
	Freq	Level	Factor	Level	Line	Limit	Remark
	MHz	dBuV	dB	dBuV	dBuV	dВ	
1	0.305	51.72	0.15	51.87	79.00	-27.13	Peak
2	0.358	52.75	0.17	52.92	79.00	-26.08	Peak
3	0.535	52.02	0.21	52.24	73.00	-20.76	Peak
4	1.772	43.16	0.30	43.46	73.00	-29.54	Peak
5	2.133	44.05	0.32	44.37	73.00	-28.63	Peak
6	3.623	42.04	0.38	42.42	73.00	-30.58	Peak
7	11.996	41.49	1.06	42.56	73.00	-30.44	Peak



No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C.

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 34 File#: 50520214CA.EMI Date: 2005-06-01 Time: 15:22:07



(Conduction A)

Trace: 33 32 Ref Trace:

Condition: COMMON MODE Report No. : 50520214
Test Engr. : MATT HSU

Company : AAEON Technology Inc.

EUT : AEC-6850

Test Config : EUT / ALL PERIPHERALS

Type of Test: EN 55022 CLASS A

Mode of Op. : 100Mbps / worst

Page: 1	1
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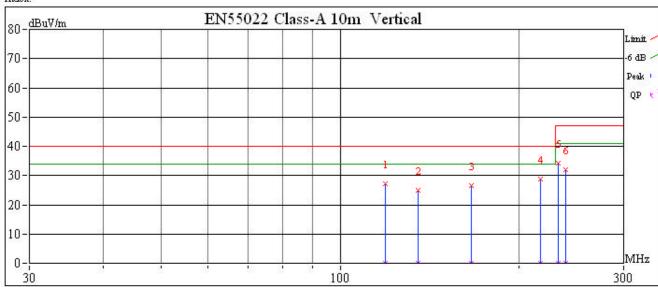
		Read			Limit	Over	
	Freq	Level	Factor	Level	Line	Limit	Remark
	\mathtt{MHz}	dBuV	dВ	dBuV	dBuV	dВ	
1	0.302	42.23	10.47	52.70	91.19	-38.49	Peak
2	5.898	48.71	10.30	59.01	87.00	-27.99	Peak
3	9.451	49.27	10.27	59.54	87.00	-27.46	Peak
4	12.188	51.54	10.29	61.83	87.00	-25.17	Peak
5	13.408	51.44	10.31	61.75	87.00	-25.25	Peak
6	15.552	50.37	10.32	60.69	87.00	-26.31	Peak
7	26.001	48.56	10.36	58.92	87.00	-28.08	Peak

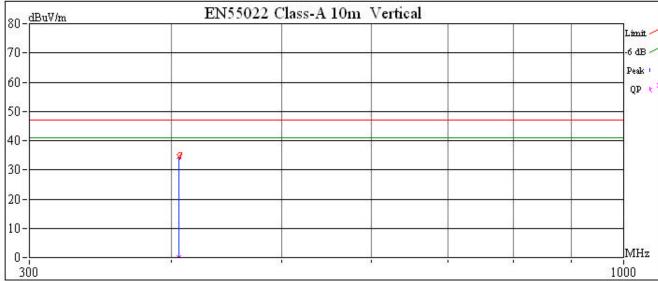
Custom Name: AAEON Technology Inc.

Model Name: AEC-6850 Test Mode: NORMAL MODE Project No.: 50520214 Engineer Name: ALEX PAN

Date: 2005-06-17







	Freq(MHz)	Peak(dBuV/m)	QP(dBuV/m)	Margin(dB)	Limit(dBuV/m)	Reading(dBuV)	Factor(dB)	Height	Degree	Comment
1	119.3000	27.16		-12.84	40.00	41.87	-14.71	100	51	
2	135.3300	25.08	i de la companya de l	-14.92	40.00	40.29	-15.21	100	51	
3	166.2600	26.61		-13.39	40.00	42.52	-15.91	100	51	
4	217.2400	28.86		-11.14	40.00	43.78	-14.92	100	51	
5	232.8900	34.39	ē.	-12.61	47.00	47.96	-13.57	100	51	
6	239.9600	32.15		-14.85	47.00	45.12	-12.97	100	51	
7	405.8700	34.42	2	-12.58	47.00	41.04	-6.62	100	51	
			<u> </u>			0				
_										
			.e.	e i		8	13			
_			5-	100 m						

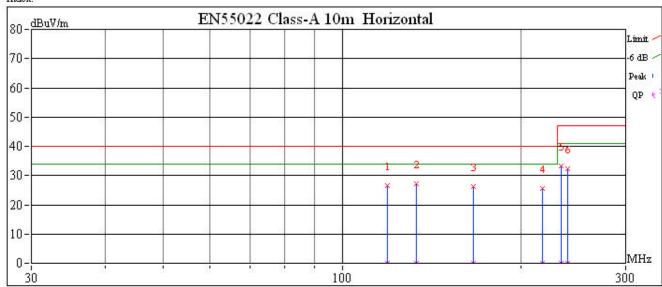


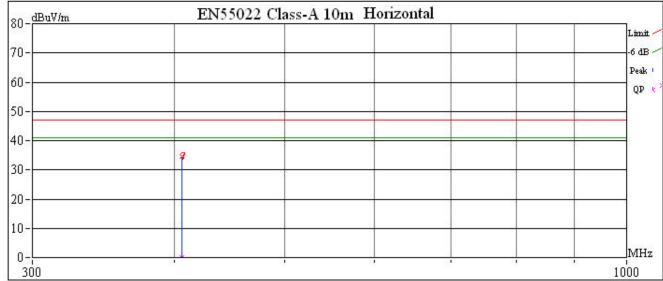
Custom Name: AAEON Technology Inc.

Model Name: AEC-6850 Test Mode: NORMAL MODE Project No.: 50520214 Engineer Name: ALEX PAN

Date: 2005-06-17







	Freq(MHz)	Peak(dBuV/m)	QP(dBuV/m)	Margin(dB)	Limit(dBuV/m)	Reading(dBuV)	Factor(dB)	Height	Degree	Comment
1	119.2150	26.51		-13.49	40.00	41.23	-14.72	100	51	
2	133.5200	27.25	i)	-12.75	40.00	42.39	-15.14	100	51	
3	166.2900	26.18		-13.82	40.00	42.09	-15.91	100	51	
4	217.4100	25.50		-14.50	40.00	40.41	-14.91	100	51	
5	233.2700	33.42	e.	-13.58	47.00	46.96	-13.54	100	51	
6	240.0700	32.27		-14.73	47.00	45.23	-12.96	100	51	
7	406.1900	34.52	22	-12.48	47.00	41.13	-6.61	100	51	
						0				
			10 10			5				
-			is is	A	8 S) (A) (A) (A) (A) (A) (A) (A) (A) (A) (A	8		50 8 1 50 8 1	
						~	l i			